# International Rectifier

### **PRELIMINARY**

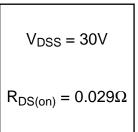
**IRF7313** 

HEXFET® Power MOSFET

## Generation V Technology

- Ultra Low On-Resistance
- Dual N-Channel MOSFET
- Surface Mount
- Fully Avalanche Rated

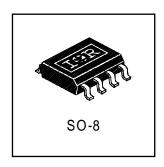
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## **Description**

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The SO-8 has been modified through a customized leadframe for enhanced thermal characteristics and multiple-die capability making it ideal in a variety of power applications. With these improvements, multiple devices can be used in an application with dramatically reduced board space. The package is designed for vapor phase, infra red, or wave soldering techniques.



## Absolute Maximum Ratings (T<sub>A</sub> = 25°C Unless Otherwise Noted)

		Symbol	Maximum	Units	
Drain-Source Voltage		V <sub>DS</sub>	30	v	
Gate-Source Voltage		$V_{GS}$	± 20		
Continuous Drain Current®	$T_A = 25^{\circ}C$	,	6.5		
Continuous Diain Current®	$T_A = 70$ °C	I <sub>D</sub>	5.2	A	
Pulsed Drain Current		I <sub>DM</sub>	30		
Continuous Source Current (Diode Conduction)		Is	2.5		
Maximum Power Dissipation S	T <sub>A</sub> = 25°C	P <sub>D</sub>	2.0	_ w	
	$T_A = 70$ °C	''	1.3	vv	
Single Pulse Avalanche Energy ②		E <sub>AS</sub>	82	mJ	
Avalanche Current		I <sub>AR</sub>	4.0	Α	
Repetitive Avalanche Energy		E <sub>AR</sub>	0.20	mJ	
Peak Diode Recovery dv/dt ③		dv/dt	5.8	V/ ns	
Junction and Storage Temperature Range		$T_{J_1}T_{STG}$	-55 to + 150	°C	

## **Thermal Resistance Ratings**

Parameter	Symbol	Limit	Units
Maximum Junction-to-Ambient®	$R_{\theta JA}$	62.5	°C/W

## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

-				·	
Parameter	Min.	Тур.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage	30			V	$V_{GS} = 0V, I_D = 250\mu A$
Breakdown Voltage Temp. Coefficient		0.022		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
Static Drain-to-Source On-Resistance		0.023	0.029	0	V <sub>GS</sub> = 10V, I <sub>D</sub> = 5.8A ⊕
		0.032	0.046		$V_{GS} = 4.5V, I_D = 4.7A$ ④
Gate Threshold Voltage	1.0			V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
Forward Transconductance		14		S	$V_{DS} = 15V, I_D = 5.8A$
Drain-to-Source Leakage Current			1.0		$V_{DS} = 24V, V_{GS} = 0V$
Drain-to-cource Leakage Current			25	μΑ	$V_{DS} = 24V, V_{GS} = 0V, T_{J} = 55^{\circ}C$
Gate-to-Source Forward Leakage			100	nΔ	$V_{GS} = 20V$
Gate-to-Source Reverse Leakage			-100	11/	$V_{GS} = -20V$
Total Gate Charge		22	33		$I_D = 5.8A$
Gate-to-Source Charge		2.6	3.9	nC	$V_{DS} = 15V$
Gate-to-Drain ("Miller") Charge		6.4	9.6	1	V <sub>GS</sub> = 10V, See Fig. 10 ④
Turn-On Delay Time		8.1	12		V <sub>DD</sub> = 15V
Rise Time		8.9	13	ne	$I_D = 1.0A$
Turn-Off Delay Time		26	39	ns	$R_G = 6.0\Omega$
Fall Time		17	26		$R_D = 15\Omega \ \oplus$
Input Capacitance		650			V <sub>GS</sub> = 0V
Output Capacitance	_	320		pF	$V_{DS} = 25V$
Reverse Transfer Capacitance		130			f = 1.0MHz, See Fig. 9
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Input Capacitance Output Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage  Forward Transconductance Drain-to-Source Leakage Current  Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Input Capacitance	Drain-to-Source Breakdown Voltage         30           Breakdown Voltage Temp. Coefficient         — 0.022           Static Drain-to-Source On-Resistance         — 0.032           Gate Threshold Voltage         1.0           Forward Transconductance         — 14           Drain-to-Source Leakage Current         — —           Gate-to-Source Forward Leakage         — —           Gate-to-Source Reverse Leakage         — —           Total Gate Charge         — 22           Gate-to-Source Charge         — 2.6           Gate-to-Drain ("Miller") Charge         — 6.4           Turn-On Delay Time         — 8.1           Rise Time         — 8.9           Turn-Off Delay Time         — 26           Fall Time         — 17           Input Capacitance         — 650           Output Capacitance         — 320	Drain-to-Source Breakdown Voltage         30         —	Drain-to-Source Breakdown Voltage         30         —         V           Breakdown Voltage Temp. Coefficient         —         0.022         —         V/°C           Static Drain-to-Source On-Resistance         —         0.032         0.046         Ω           Gate Threshold Voltage         1.0         —         V           Forward Transconductance         —         14         —         S           Drain-to-Source Leakage Current         —         —         1.0         —         —         V           Gate-to-Source Forward Leakage         —         —         1.00         —         nA           Gate-to-Source Reverse Leakage         —         —         100         nA           Total Gate Charge         —         2.6         3.9         nC           Gate-to-Source Charge         —         2.6         3.9         nC           Gate-to-Drain ("Miller") Charge         —         6.4         9.6         nC           Turn-On Delay Time         —         8.9         13         nS           Turn-Off Delay Time         —         2.6         39         nS           Fall Time         —         2.6         3.9         nS           Input Ca

## **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			2.5	_	MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			30	- A	integral reverse p-n junction diode.
$V_{SD}$	Diode Forward Voltage		0.78	1.0	V	$T_J = 25$ °C, $I_S = 1.7$ A, $V_{GS} = 0$ V ③
t <sub>rr</sub>	Reverse Recovery Time		45	68	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 1.7A
Q <sub>rr</sub>	Reverse RecoveryCharge		58	87	nC	di/dt = 100A/µs ③

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- $\label{eq:targent} \begin{tabular}{ll} \begi$

- $\label{eq:loss} \begin{array}{l} \text{ } 3 \text{ } I_{SD} \leq 4.0 \text{A}, \text{ di/dt} \leq 74 \text{A/}\mu\text{s}, \text{ } V_{DD} \leq V_{(BR)DSS}, \\ T_{J} \leq 150^{\circ}\text{C} \end{array}$
- ④ Pulse width  $\leq$  300µs; duty cycle  $\leq$  2%.
- ⑤ Surface mounted on FR-4 board,  $t \le 10$ sec.

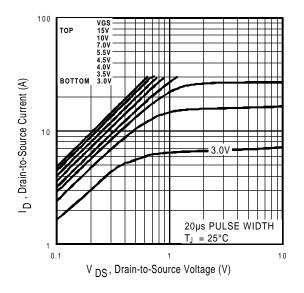


Fig 1. Typical Output Characteristics

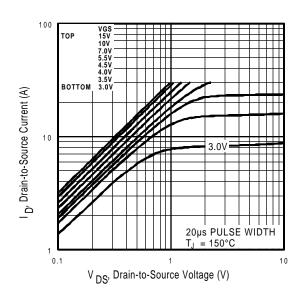


Fig 2. Typical Output Characteristics

**VDS** 

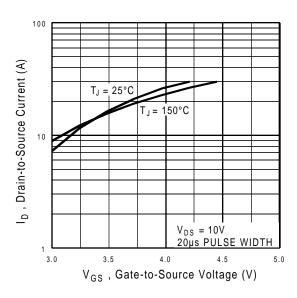
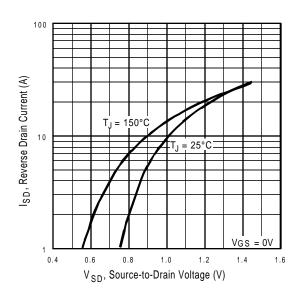
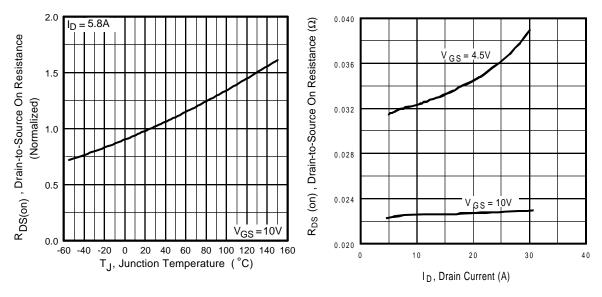


Fig 3. Typical Transfer Characteristics

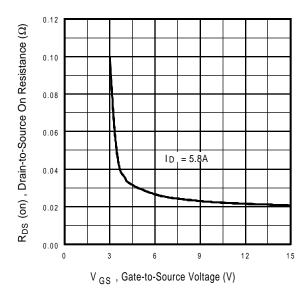


**Fig 4.** Typical Source-Drain Diode Forward Voltage



**Fig 5.** Normalized On-Resistance Vs. Temperature

Fig 6. Typical On-Resistance Vs. Drain Current



**Fig 7.** Typical On-Resistance Vs. Gate Voltage

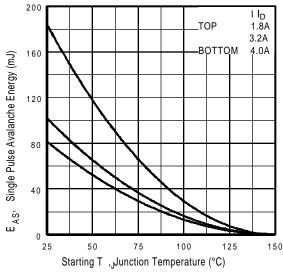
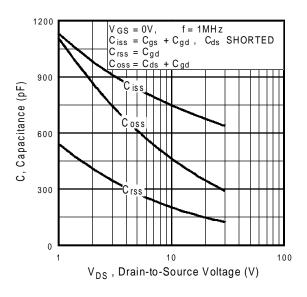
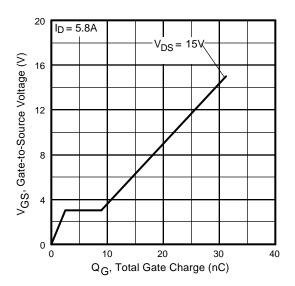


Fig 8. Maximum Avalanche Energy Vs. Drain Current



**Fig 9.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 10.** Typical Gate Charge Vs. Gate-to-Source Voltage

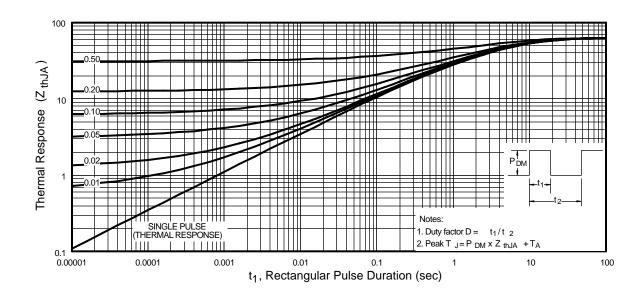
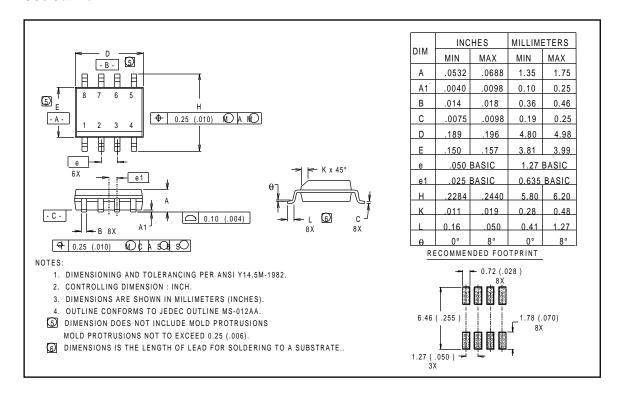


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

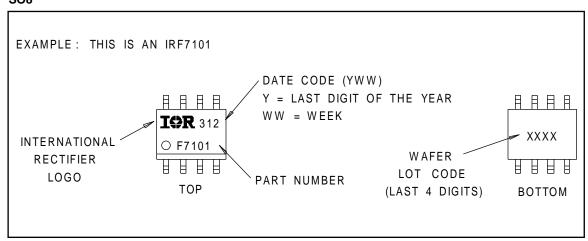
## Package Outline

#### **SO8 Outline**



## Part Marking Information

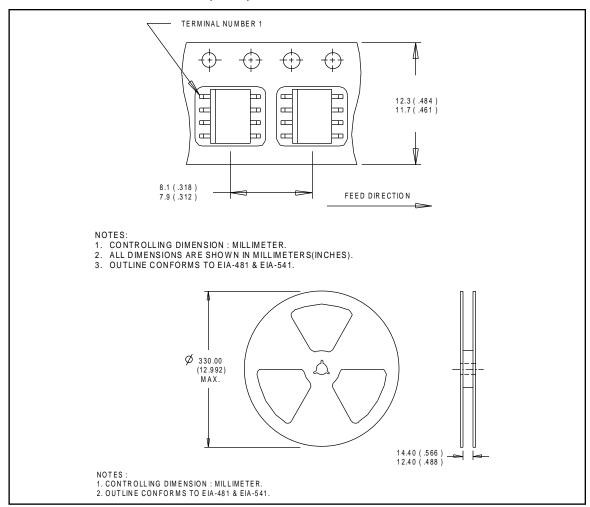
#### **SO8**



## Tape & Reel Information

#### **SO8**

Dimensions are shown in millimeters (inches)



## International Rectifier

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